

Automotive-grade N-channel 60 V, 19 mΩ typ., 24 A STripFET™ F6 Power MOSFET in a DPAK package

Datasheet - production data

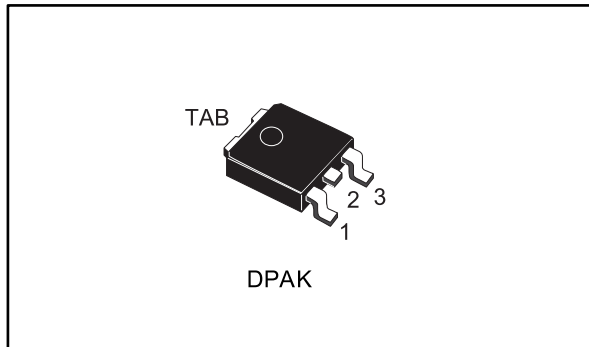
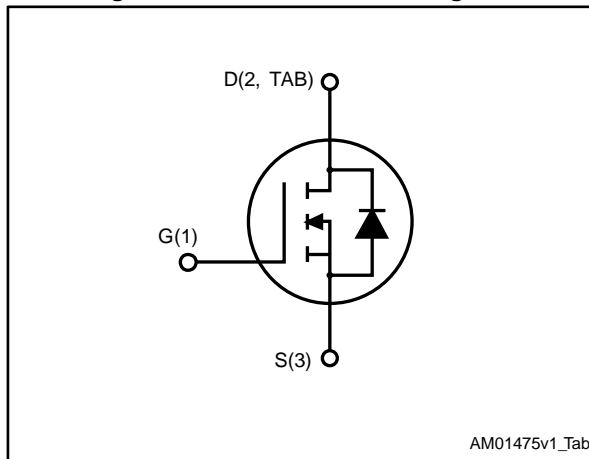


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	P _{TOT}
STD30N6LF6AG	60 V	25 mΩ	24 A	40 W

- Designed for automotive applications and AEC-Q101 qualified
- Very low on-resistance
- Very low gate charge
- High avalanche ruggedness
- Low gate drive power loss

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using the STripFET™ F6 technology with a new trench gate structure. The resulting Power MOSFET exhibits very low R_{DS(on)} in all packages.

Table 1: Device summary

Order code	Marking	Package	Packing
STD30N6LF6AG	30N6LF6	DPAK	Tape and Reel

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	60	V
V_{GS}	Gate-source voltage	± 20	V
I_D	Drain current (continuous) at $T_{case} = 25\text{ °C}$	24	A
	Drain current (continuous) at $T_{case} = 100\text{ °C}$	17	
$I_{DM}^{(1)}$	Drain current (pulsed)	96	A
P_{TOT}	Total dissipation at $T_{case} = 25\text{ °C}$	40	W
$E_{AS}^{(2)}$	Single pulse avalanche energy	130	mJ
T_{stg}	Storage temperature	-55 to 175	°C
T_j	Operating junction temperature		

Notes:

⁽¹⁾ Pulse width is limited by safe operating area.

⁽²⁾ starting $T_j = 25\text{ °C}$, $I_D = 24\text{ A}$, $V_{DD} = 43.5\text{ V}$.

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	3.75	°C/W
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb	35	

Notes:

⁽¹⁾ When mounted on a 1-inch² FR-4 board, 2 oz Cu.

2 Electrical characteristics

($T_{\text{case}} = 25\text{ °C}$ unless otherwise specified)

Table 4: Static

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	60			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$			1	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$, $T_{\text{case}} = 125\text{ °C}$			100	
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 20\text{ V}$			± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	1		2.5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 12\text{ A}$		19	25	m Ω
		$V_{GS} = 4.5\text{ V}$, $I_D = 12\text{ A}$		24	30	

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	1320	-	μF
C_{oss}	Output capacitance		-	88.5	-	
C_{rss}	Reverse transfer capacitance		-	58	-	
Q_g	Total gate charge	$V_{DD} = 30\text{ V}$, $I_D = 24\text{ A}$, $V_{GS} = 10\text{ V}$ (see	-	26	-	nC
Q_{gs}	Gate-source charge		-	6	-	
Q_{gd}	Gate-drain charge		-	3.3	-	

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30\text{ V}$, $I_D = 12\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ (see	-	10	-	ns
t_r	Rise time		-	19	-	
$t_{d(off)}$	Turn-off delay time		-	56	-	
t_f	Fall time		-	7	-	

Table 7: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		24	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		96	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0\text{ V}$, $I_{SD} = 24\text{ A}$	-		1.3	V
t_{rr}	Reverse recovery time	$I_{SD} = 24\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 48\text{ V}$, $T_J = 150\text{ °C}$ (see	-	22.4		ns
Q_{rr}	Reverse recovery charge		-	22.2		nC
I_{RRM}	Reverse recovery current		-	2		A

Notes:

⁽¹⁾ Current is limited by package.

⁽²⁾ Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

